Buffer Layer Strategic Research and Development

OAK RIDGE NATIONAL LABORATORY

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FY 2002 EE/RE Funding: \$750 k: 2.5 FTE Staff, 2 FTE Post-Doctoral Fellows



Partnerships:

University Collaborators

- University of Florida: D. P. Norton
- University of Wisconsin: D. C. Larbalestier, M. Feldman
- University of Kansas: J. Z. Wu

National Laboratory Collaborators

- Argonne National Laboratory: Balu Balachandran, D. Miller, B. Ma
- National Institute of Standards & Technology:

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- Sandia National Laboratory: M. Siegal, P. Clem
- Los Alamos National Laboratory: P. Arendt, S. Foltyn, T. Holesinger

Industrial Licensees/Partners

• American Superconductor, 3M, Microcoating Technologies, Neocera, Oxford Superconducting Technology



PURPOSE: To develop a basic understanding of and practical synthesis paths for epitaxial buffer layers on textured metal tapes for coated conductors.

FY2002 OBJECTIVES:

- Optimize sulfur treatment to demonstrate consistent epitaxial seed layer deposition
- Optimize buffer layers on metal alloy substrates
- Investigate single buffer-layers for YBCO/RABiTS
 Develop cap-buffer layers for MgO-buffered tapes (collaborative with LANL and ANL)

Explore feasibility of buffers on copper substrates for YBCO coatings



OUTLINE

• FY 2002 Results:

- Studies of sulfur superstructure and influence on epitaxial growth of oxide buffer layers of different structural classes
- Buffer layers on emerging metal tapes

Non-magnetic copper and NiCr alloys

- Single buffer layers for YBCO/RABiTS
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• FY 2002 Performance and Plans for FY 2003

Research Integration





Characteristics of the c(2×2) Superstructure on Ni

• Stable at high temperature

 c(2×2) does not transform to other structures

• Forms by segregation and/or adsorption with identical results on seed layer growth



<mark>S/Ni</mark> = 0.5





Ni

c(2 × 2)-5

The c(2×2)-S Superstructure Promotes Epitaxy







H₂S Treatment Controls the c(2×2)-S **Needed for Buffer Layer Epitaxy**

Exposure times of few s are sufficient to produce a complete $c(2\times 2)$ layer



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S Treatment Transferred to AMSC Yields Consistent Epitaxial Seed Layer Deposition

Reel-to-reel X-ray on 3-meter long Y₂O₃ seed on sulfurized Ni-W tape



Seed Layers that Require c (2×2)-S

fluorite	Seed Layer	H ₂ O pressure	O ₂ pressure
		(Torr)	(Torr)
	CeO ₂	1×10 ⁻⁵	~ 7×10 ⁻⁸
	YSZ	1×10 ⁻⁸	≤ 1×10-9
	Y ₂ O ₃	1×10 ⁻⁵	~ 7×10 ⁻⁸
	Gd ₂ O ₃	1×10 ⁻⁵	~ 7×10 ⁻⁸
	SrTiO ₃	6×10 ⁻⁸	≥ 1×10 ⁻⁹
	LaMnO ₃	6×10 ⁻³	≥ 10-6

perovskite

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Epitaxial Growth of CeO₂ and STO on Pd Requires c (2×2)-S



Seed Layers That do not Want the S Superstructure: MgO

- MgO grows cube on cube on clean Pd
- Initial growth is layer-by-layer
- $c(2\times 2)$ -S disturbs MgO growth





After 250 s



Why does MgO behave differently?

Structural differences

- No (001) oxygen planes, strong Mg - O bond, no structural vacancies
- Reported epitaxy on clean Ag (S. Schintke et al. Phys. Rev. Lett. 87 (2001) 276801)
- Interesting properties of MgO
 - Good oxygen diffusion barrier $D_{MgO}(800^{\circ}C) \cong 10^{-28} \text{ cm}^2/\text{s}$ $D_{STO}(800^{\circ}C) = 2 \times 10^{-12} \text{ cm}^2/\text{s}$
 - Low temperature deposition





The Effect of S on Solution Buffer Layer Growth

- On Ni and Ni-3%W substrates with optimum S (~100 %), buffers with perfect cube texture were reproducibly produced
- On substrates with less S, irreproducible results were obtained



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Summary

- Control of the S superstructure by on-line H₂S exposure has produced consistent epitaxial seed layer deposition at ORNL and AMSC
- The study of the influence of S on seed layer epitaxy was extended to a wide range of oxides showing a behavior common to several classes of materials
- Not all oxide seed layers want the S template: MgO behaves differently than oxides with fluorite or perovskite structure
- Evidence was provided for the importance of S in growth of solution seed layers



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Issues Involved in Buffer Layer Deposition on Ni-13%Cr

- c(2×2)-S superstructure has the same role as in pure Ni
- Cr-O-free surface only stable below P(O₂)=1.0×10⁻⁸ Torr
 - YSZ is a viable seed layer but needs UHV
 - $J_c = 0.4 \text{ MA/cm}^2$ demonstrated on YBCO/CeO₂(80 *nm*)/YSZ(170 *nm*)/Ni-13%Cr
- Need for a low-deposition-temperature seed layer
 - MgO + Pd overlayer: only if Pd can be thin and no Pd/Ni interdiffusion



Pd/Ni Interdiffusion Studies

- Interdiffusion occurs at 500 ℃ and is dramatic at 600 ℃
- At T = 400 $^{\circ}$ C there is no interdiffusion \Rightarrow Pd film can be thin





Alternative Architecture for Ni-alloy-Based Conductors

Thin metal layer; no need for sulfurization; low-temperature seed layer deposition





Buffer Layers on Cu

• Why is Cu interesting?

- Inexpensive
- Low resistivity, no need of stabilizing cap \Rightarrow higher J_E (for totally conducting architectures)
- Can be strengthened without increasing resistivity

Important Issues

- Higher thermal expansion than Ni
- Surface interaction with S different than in Ni
- Cu-O less self-limiting than Ni-O at high temperatures



S Superstructures on (001) Cu

- S forms only a $p(2\times 2)$ superstructure on Cu
- Epitaxy of STO and CeO₂ requires S superstructure



Cu is a Challenging Substrate

- The standard architecture is not suitable for YBCO deposition
 - disruptive oxidation/delamination
 - not a sufficient O/Cu diffusion barrier
- Pd, Ag, Ni, Au metal overlayers are not compatible with Cu surface
 - surface alloying, orientation other than (001)
- Would MgO be a suitable passivating buffer layer?



Control Study of Buffer Layers Performance on Cu Epitaxial Films on STO and MgO Substrates



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TiN Provides the Cu Diffusion Barrier Needed for YBCO Deposition





J_c = 3.5 MA/cm² YBCO on Buffered Cu Films

• clean interfaces after YBCO deposition, non detectable Cu-O/Ti-O



High J_c YBCO on Buffered Single Crystal Cu

• Dense, crack-free microstructure



T-BATTEL

Summary

- A RABiTS architecture that uses MgO and LaMnO₃ with no need for sulfurization gives $J_c = 3 \text{ MA/cm}^2 \text{ Ni-13\%Cr}$ substrates
- Study of Cu surface has highlighted differences in S adsorption/segregation and seed layer nucleation as compared to other fcc metal surfaces
- High J_c was demonstrated for the first time on Cu using TiN as Cu diffusion barrier



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FY 2002 Performance and Plans for FY 2003 Research Integration



RABiTS process with a standard architecture



YBCO by ex-situ BaF₂/TFA process or PLD (0.2 μm)

Best J_c 2.0 x 10⁶ A/cm² at 77 K

- Barrier and cap layers by rf sputtering
- Seed layers by e-beam or dipcoating

Objective: To develop a simple alternative buffer architecture Candidates: LaMnO₃ (LMO); La₂Zr₂O₇ (LZO) Techniques: rf sputtering and solution process



Developed a Conductive YBCO/ La_{0.7}Sr_{0.3}MnO₃ /Ni **Multilayer Architecture**

- YBCO (PLD); $T_c = 88 \text{ K}$ Good electrical coupling with Ni.
- $J_c = 0.5 \times 10^6 \text{ A/cm}^2$ (a) 77 K Overall low net resistivity ($\approx 7 \mu\Omega$ -cm), but

four-terminal res. indicates some contact barrier



Ref.: T. Aytug et al., Appl. Phys. Lett. 79, 2205 (October 2001)



SIMS depth profile analyses indicated a low level Sr contamination of YBCO, from the LSMO layer on Ni



SIMS depth profile analyses indicated a low level Sr contamination of YBCO, from the LSMO layer on STO



Textured LMO layers were deposited on both Ni and Ni-W substrates using rf sputtering



SIMS depth profile analyses indicated no contamination of both YBCO (from LMO) and LMO (from Ni) layers



Smooth microstructure of *LaMnO*₃ **Buffers**



1 μm

10 µm

Cross-section images of YBCO/LaMnO₃ on Ni-W



- NiO is formed at the LMO/Ni interface during the YBCO growth
- Ni diffusion is contained at the LMO layer
- LMO/YBCO interface is clean



PLD was used to grow YBCO films (0.2 μ m) with a J_c of over 1 MA/cm² on LMO buffered Ni and Ni-W substrates







Highly textured YBCO and LaMnO₃ buffers were grown on strong, non-magnetic Ni-Cr 13% substrates





YBCO films with a J_c of 1.2 MA/cm² on LMO buffered non-magnetic Ni-Cr 13% substrates using PLD





LaMnO₃ Buffers for non-RABiTS based YBCO Coated Conductors



Demonstrated the compatibility of LMO buffers on MgO single crystal substrates by growing YBCO films with a J_c of over 4 MA/cm² using both PLD (0.2 μ m) and Ex-situ BaF₂ (0.3 μ m) processes





An Oak Ridge – Los Alamos collaboration produced excellent results on IBAD MgO

- * Los Alamos sent high-quality IBAD MgO samples to Oak Ridge
- Oak Ridge sputtered a LaMnO₃ buffer layer on the MgO
- The samples were returned to Los Alamos for PLD YBCO

Result:

- YBCO texture 5.2° FWHM (in-plane); 1.8° FWHM (out-of-plane)
- YBCO thickness 1.65 μm
- ➢ J_c (75 K, self-field, two bridges) − 1.3 and 1.5 MA/cm²
- ➢ Equivalent I_c − 230 A/cm-width

This performance is comparable to the best single-layer results achieved by Los Alamos on IBAD MgO, and at several institutions on IBAD YSZ





Demonstrated the growth of YBCO films (0.2 μ m) with a J_c of 1.8 MA/cm² on *ORNL*-LaMnO₃ buffered *LANL*-IBAD MgO Buffers at ORNL







An Oak Ridge – Argonne collaboration resulted in demonstration of the "cube-on-cube" growth of YBCO (ORNL)/LMO (ORNL)/MgO-ISD (Argonne)

In-plane <110> $_{MgO}$ // <110> $_{LMO}$ // <110> $_{YBCO}$; (001) $_{MgO}$ // (001) $_{LMO}$ // (001) $_{YBCO}$



OAK RIDGE NATIONAL LABORATORY U. S. DEPARTMENT OF ENERGY 250 nm Dean Miller, ANL



YBCO *c*-axis inclined ~36° from substrate normal But, current conduction in basal planes



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Dean Miller, ANL



Summary

- LaMnO₃ layer has been identified as an excellent seed layer, Ni diffusion barrier layer, and a cap layer (PLD YBCO)
- YBCO films with a J_c of 1.2 MA/cm² were obtained on LMO buffered non-magnetic Ni-Cr 13% substrates
- High J_c YBCO films were produced on LMO buffered- MgO IBAD or ISD substrates









LZO seeds on Ni-3%W substrates yielded high current density YBCO films grown by PLD (FY 2001)



X-ray and microstructure of all solution LZO layers



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T_c and J_c data on PLD grown YBCO films (0.2 μm) on all solution LZO buffered Ni substrates



YBCO films (0.2 μ m) with a J_c of over 1 MA/cm² have been grown on all solution 60 nm thick LZO buffered Ni substrates using PLD



The performance of single solution buffer layers approach that of our standard three-layer architectures



Highly aligned YBCO films (0.2 μ m) have been grown on all solution 60 nm thick LZO buffered Ni-W substrates using PLD





All Solution-grown Single Buffer Layer Yielded 2 MA/cm² YBCO Conductor on Ni-W substrates





Thick PLD YBCO films on all solution LZO (60 nm) buffered Ni-W substrates





Summary

- LZO has been identified as an excellent Ni diffusion barrier layer
- YBCO films with a J_c of 2 MA/cm² were produced on all solution LZO buffered Ni-W substrates
- Efforts are being made to make long lengths of LZO layers



FY2002 Performance and FY2003 PlansFY2002 PlansFY2002 Performance

 Optimize sulfur treatment to demonstrate consistent epitaxial seed layer deposition

- Optimize buffer layers on metal alloy substrates
- Investigate single buffer-layers for YBCO/RABiTS

- Process conditions for superstructure formation identified
- Effects on epitaxial growth of vapor deposited and solution-grown oxides determined
- Growth models proposed for epitaxy of different structural classes
 - Significant tech transfer to industry
- Buffer architectures found for growth of YBCO on Ni-13%Cr and Ni-3%W
- \checkmark
- Solution-based La₂Zr₂O₇ single buffers developed on Ni-W and Ni tapes
- Sputtered LaMnO₃ single buffers developed on Ni, Ni-W, and Ni-Cr tapes



New Task(s) Added in FY 2002

FY2002 Plans (cont'd)

 Initiate development of buffer layers for YBCO coatings on copper alloys

FY2002 Performance

High-J_c films have been deposited by PLD on buffered copper films and single crystals

- Develop cap-buffer layers for MgObased tapes, in collaboration with LANL (IBAD MgO) and ANL (ISD MgO)
- ✓ High-J_c YBCO have been deposited by PLD on buffers of ORNL LaMnO₃ on LANL and ANL MgO-buffered alloy tapes



FY2003 Plans

- Research and develop faster, potentially lower cost, and simpler RABiTS buffer-layer architectures that are compatible with exsitu BaF₂ or MOD YBCO processes (collaboration with SNL and AMSC)
- Continue fundamental studies of epitaxial growth on textured non-magnetic substrates, including copper and copper alloys (collaboration with U. Florida, AMSC, SUNY Buffalo and North Carolina State)
- Develop suitable buffer architectures on IBAD-MgO and ISD-MgO substrates for compatibility with ex-situ YBCO (collaboration with LANL and ANL)
- Develop viable high-rate processes to fabricate high-quality thick buffer layers by solution deposition



Research Integration

- Five CRADA teams working with ORNL staff to develop science base for buffer layers for coated conductors *3M Company; American Superconductor Corp.; MicroCoating Technologies; Neocera, Inc., Oxford Superconducting Technology*
- Collaborations with universities and other labs
 U. Wisconsin; U. Kansas; U. Florida; ANL; LANL; SNL
- Information/expertise transfer:
 - >30 publications and presentations, >20 issued patents related to RABiTS technology
 - WEB posting of Annual Report and presentations from this meeting

